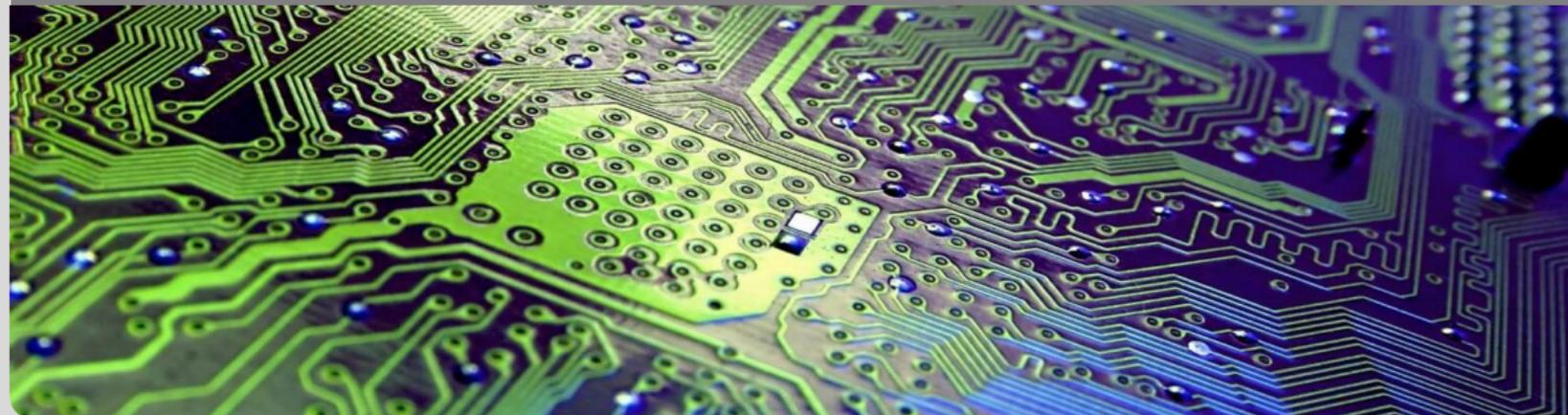


FPGAhammer: Remote Voltage Fault Attacks on Shared FPGAs, suitable for DFA on AES

Jonas Krautter, Dennis R.E. Gnad, Mehdi B. Tahoori | 10.09.2018

INSTITUTE OF COMPUTER ENGINEERING – CHAIR OF DEPENDABLE NANO COMPUTING



Motivation

- More resources per FPGA \Rightarrow **Multi-user** environments:
 - Amazon, Microsoft and introduce FPGA usage in cloud computing
 - System-on-Chip (SoC) variants, tightly coupled FPGA based systems (Xilinx PYNQ, Intel Xeon FPGA, Intel/Altera-SoCs...)
 - Accelerators deployed to partitions through partial reconfiguration
 \Rightarrow **Multi-tenant** FPGAs
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- New attack scenarios:
 - Passive on-chip side-channels¹
 - Denial-of-Service²
 - **This work: Fault attacks**
 - ...

¹Schellenberg et al., "An Inside Job: Remote Power Analysis Attacks on FPGAs", DATE 2018

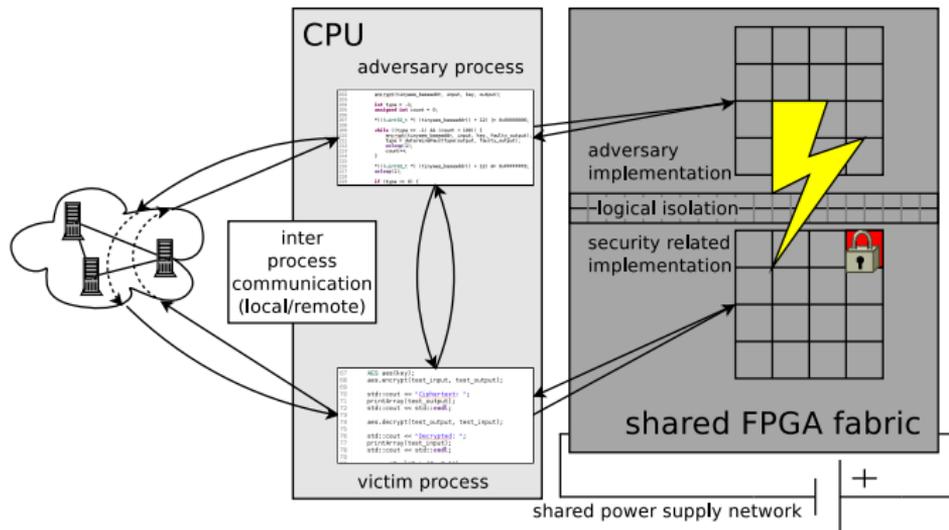
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- Proof-of-Concept work: Successful DFA on AES

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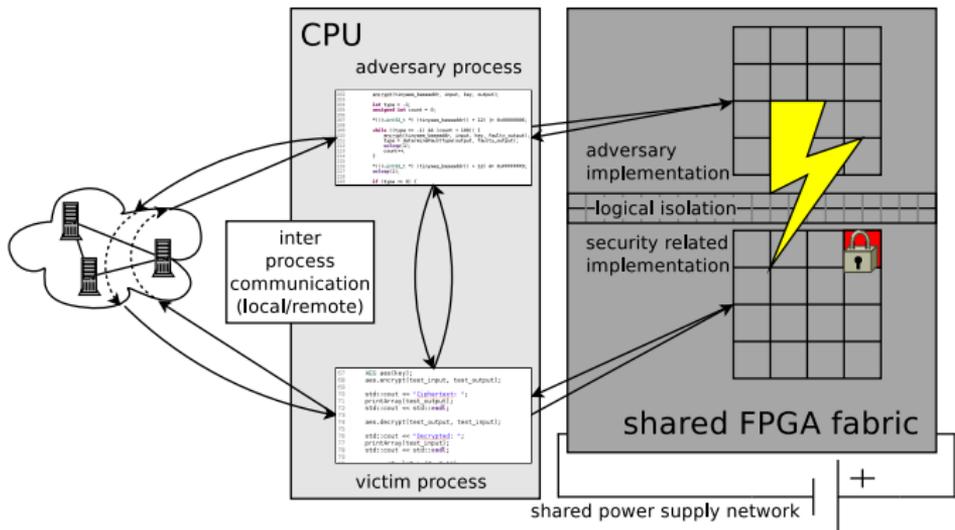
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Threat model



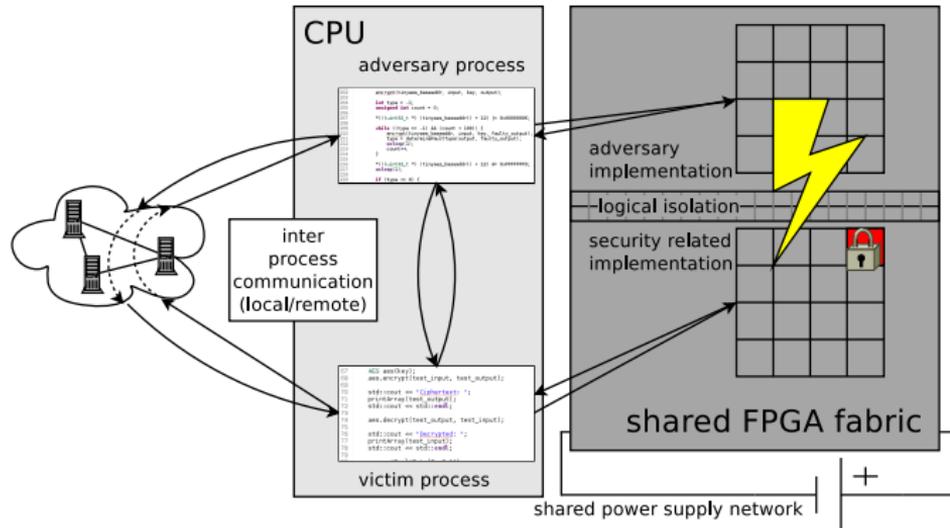
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- Attacker and victim design **logically isolated**

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- **Chosen-Plaintext Attack** scenario

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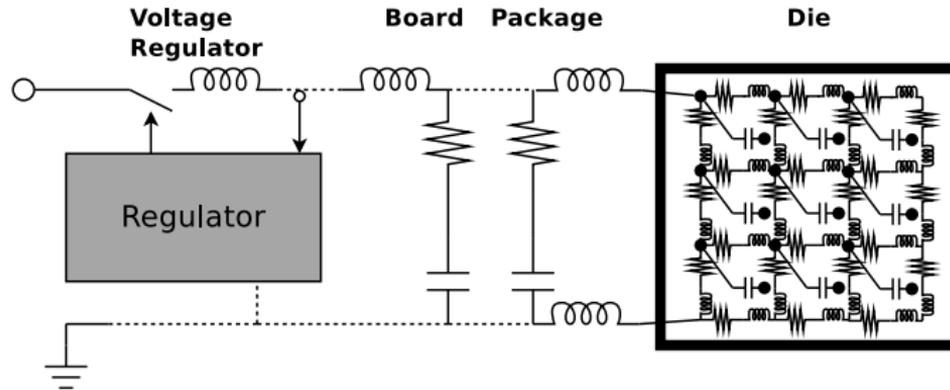
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Power Distribution Network (PDN)

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and M.B. Tahoori

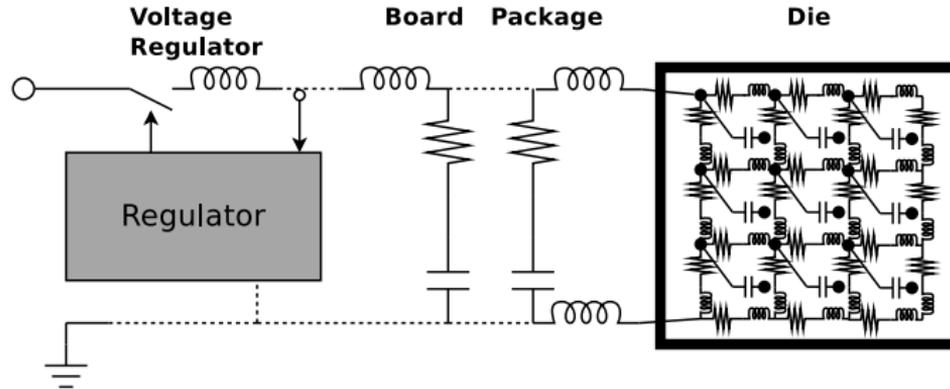
- Interconnections from the voltage regulator down to logic elements
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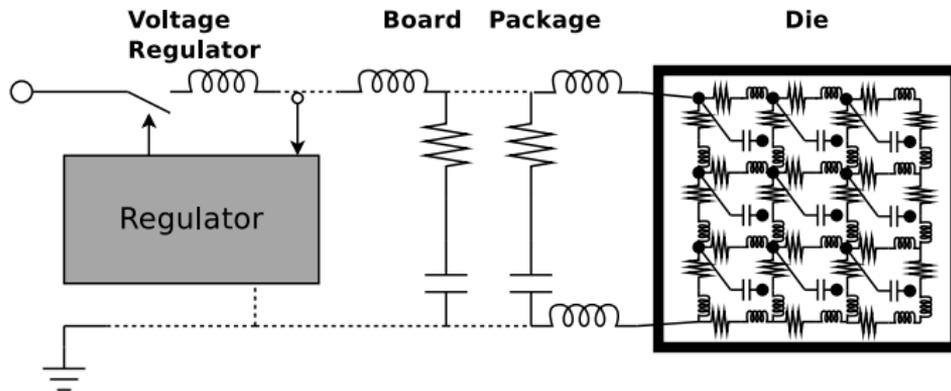
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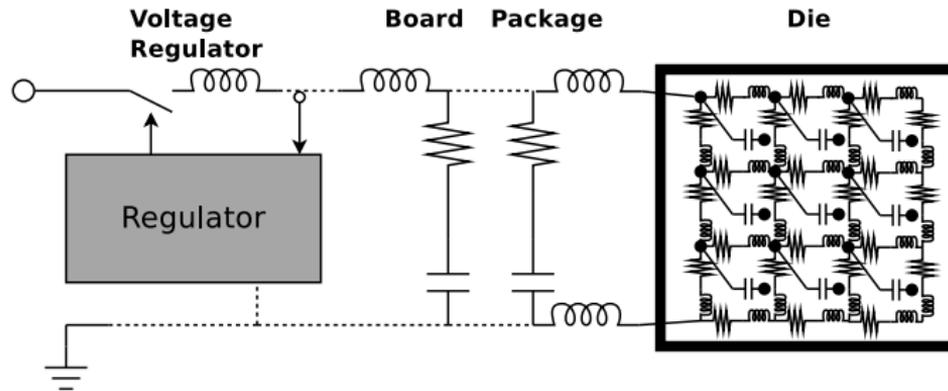
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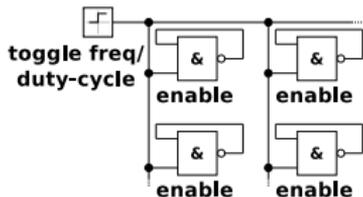


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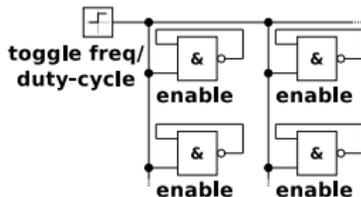
Malicious Logic



- Logic element to cause high current variation²:
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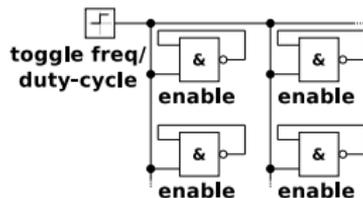


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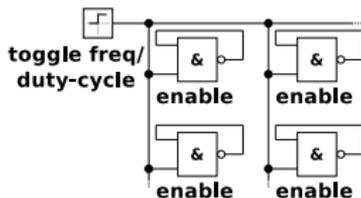


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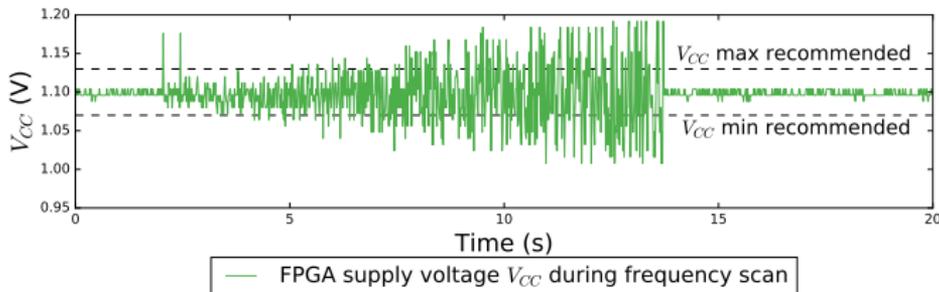
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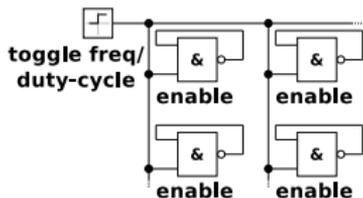
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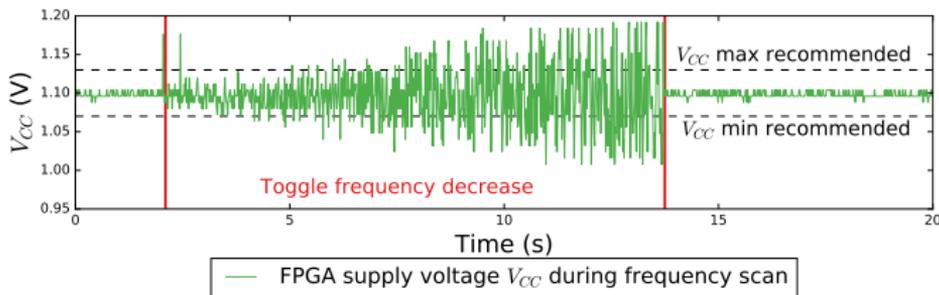
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- Differential Fault Analysis on AES³

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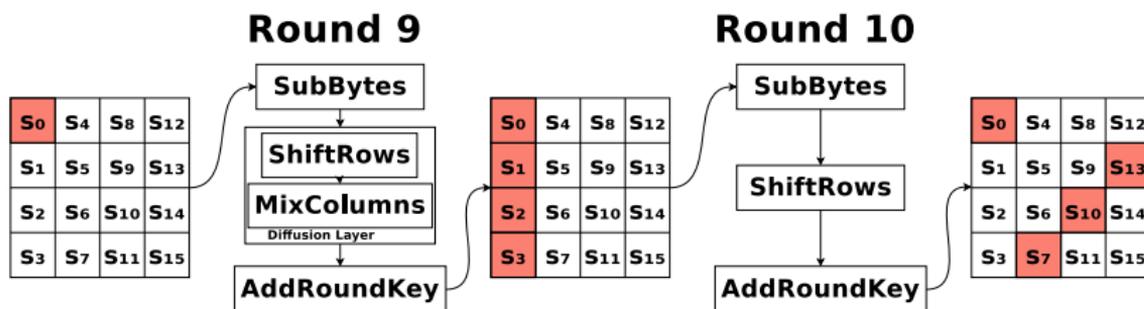
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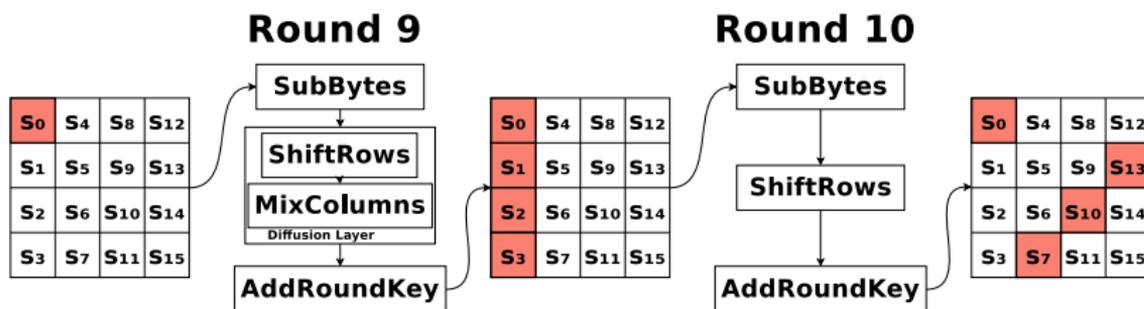
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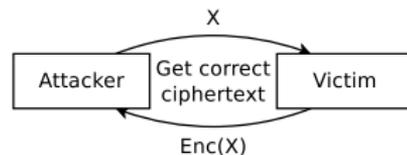


- Successful injection can be **verified**

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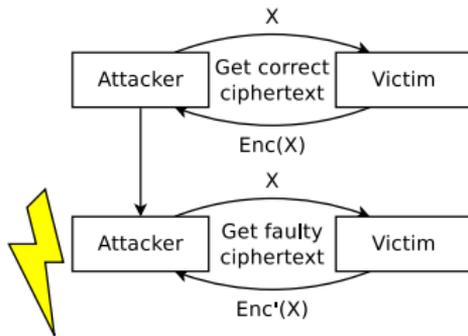
Fault Injection and Analysis

- Attacker issues encryption request to get correct ciphertext



Fault Injection and Analysis

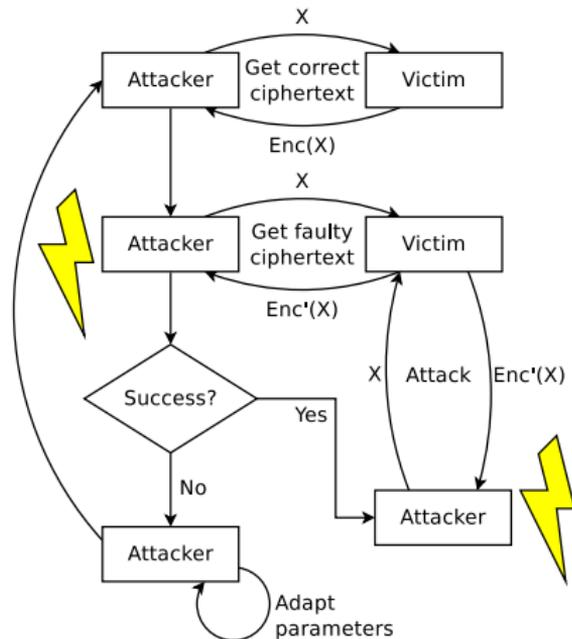
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Fault Injection and Analysis

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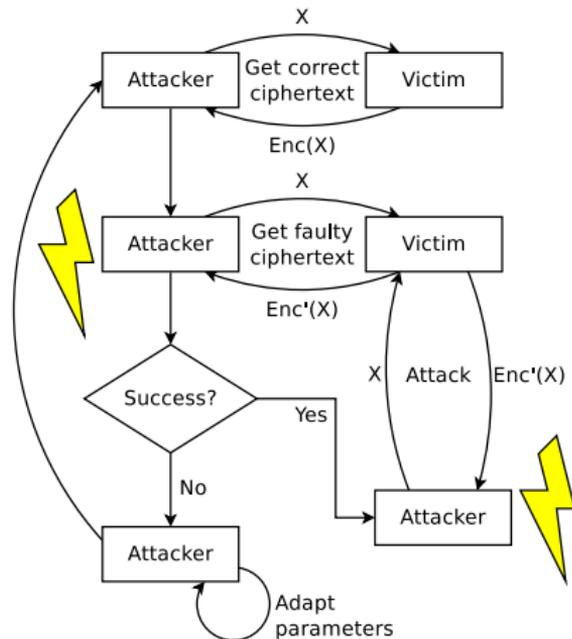
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Fault Injection and Analysis

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- Calibration is done only **once** for a specific board



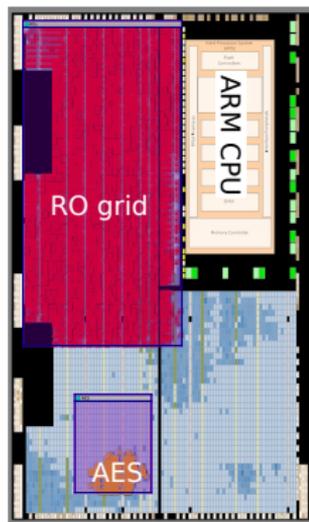
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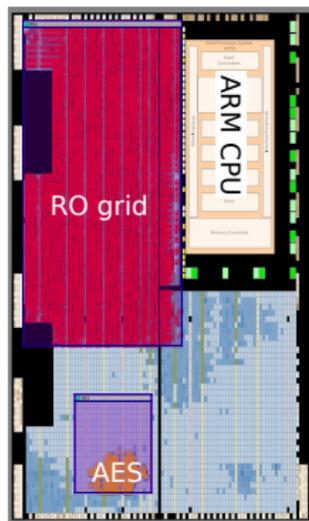
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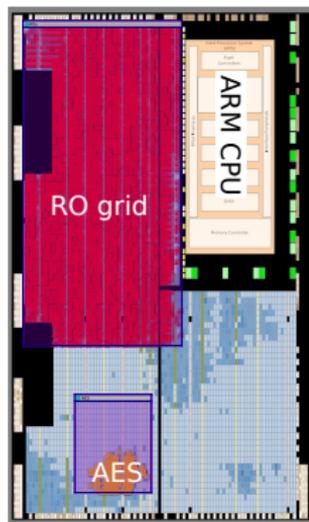
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 - 3 boards of the same type
 - 2 different boards
⇒ Show generality of attack
- Cyclone V FPGA and ARM Cortex-A9 on one chip
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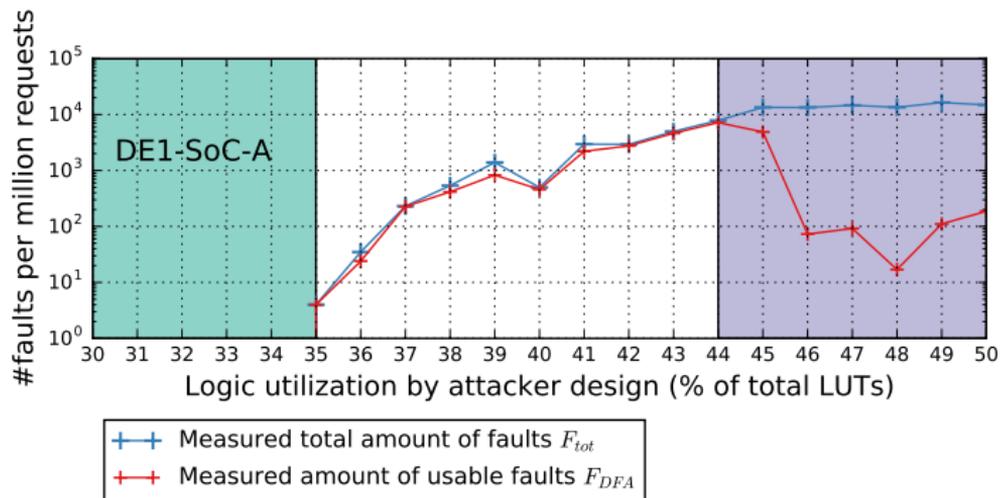
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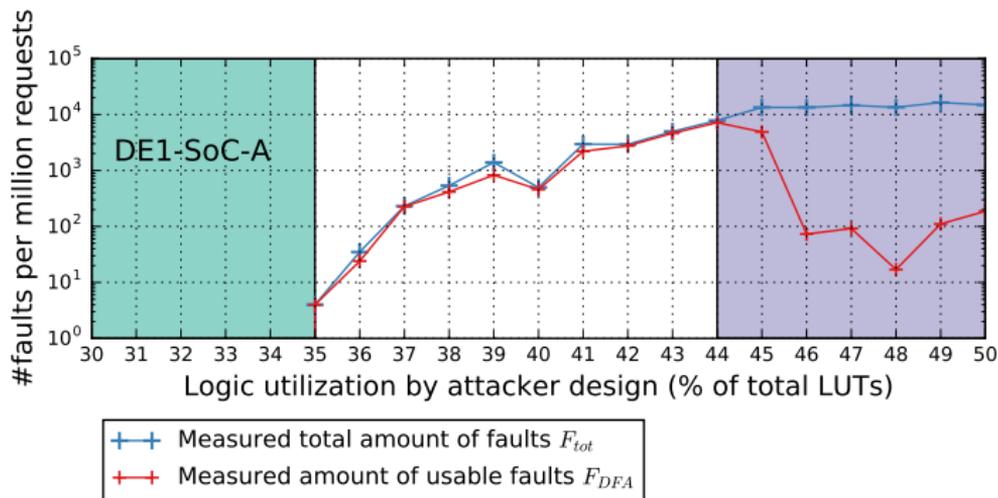
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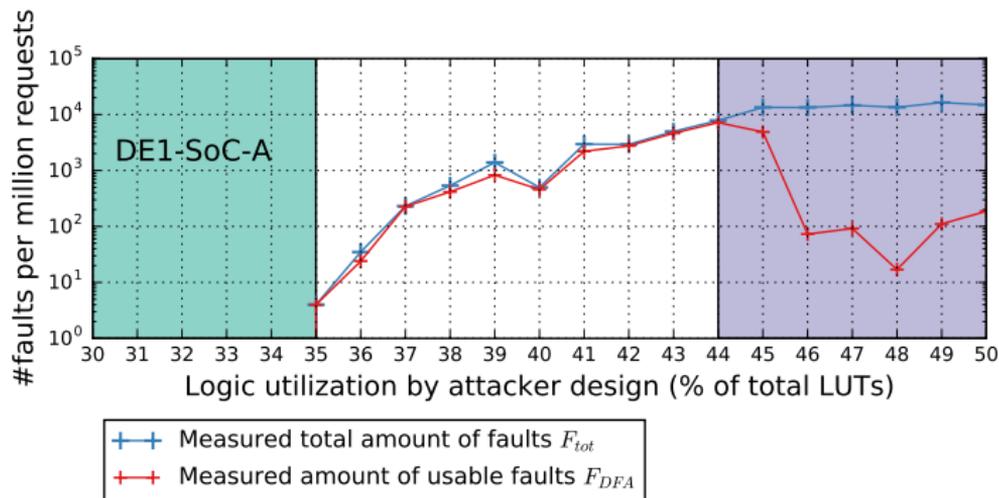
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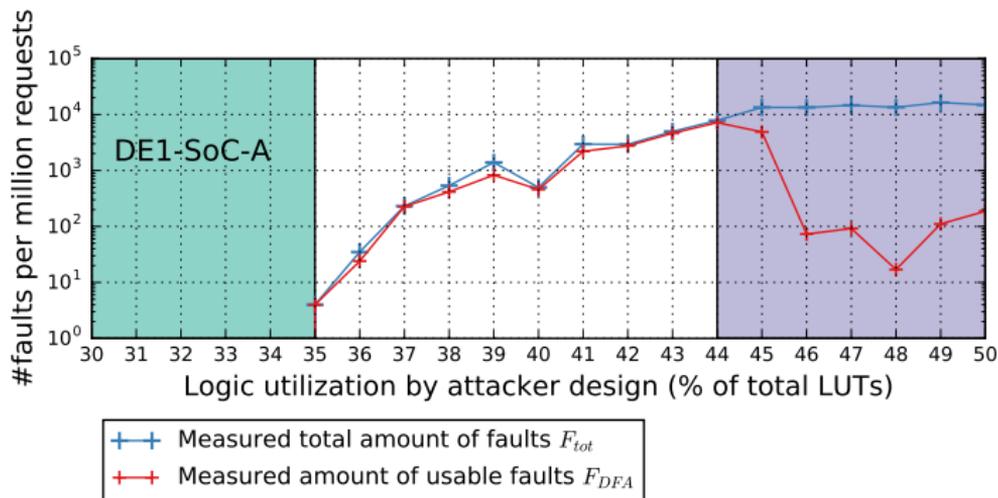
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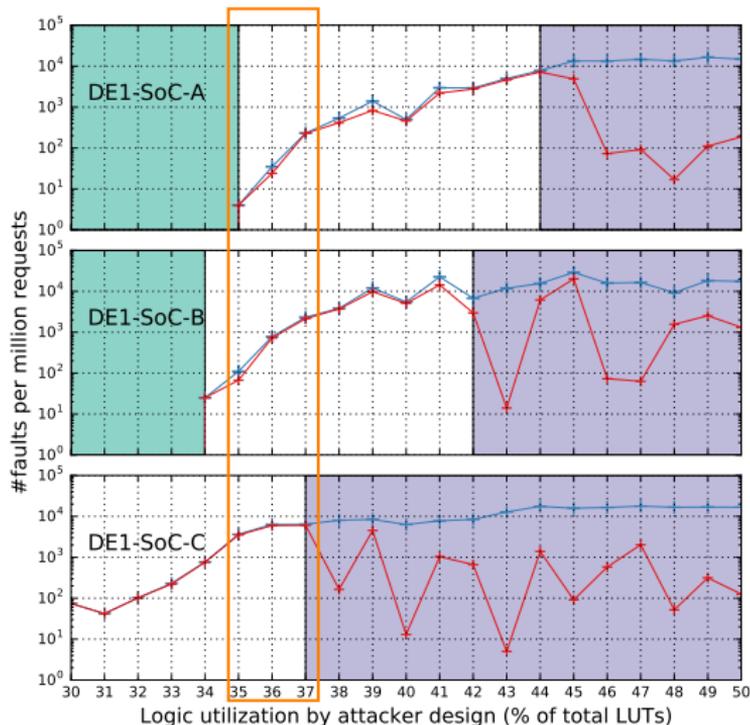
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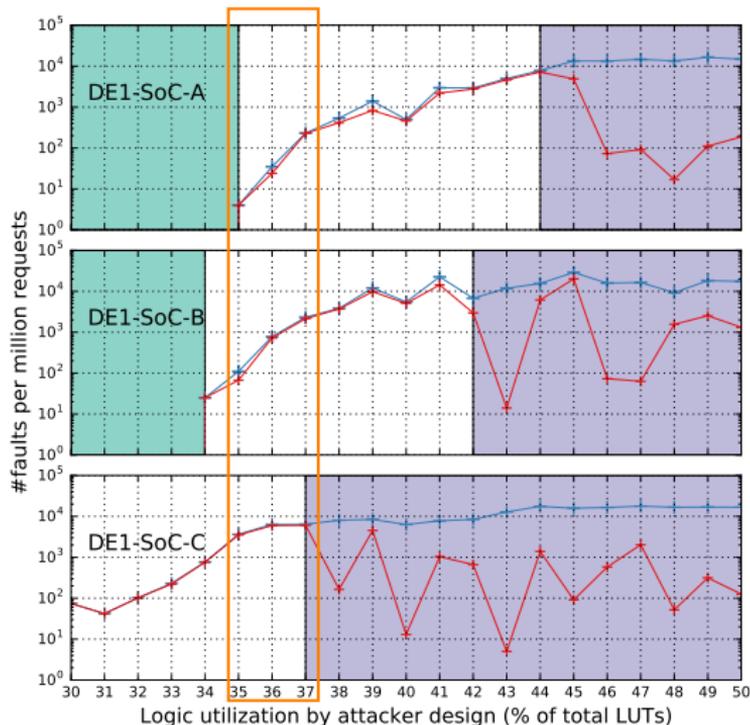
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- Extended experiments:
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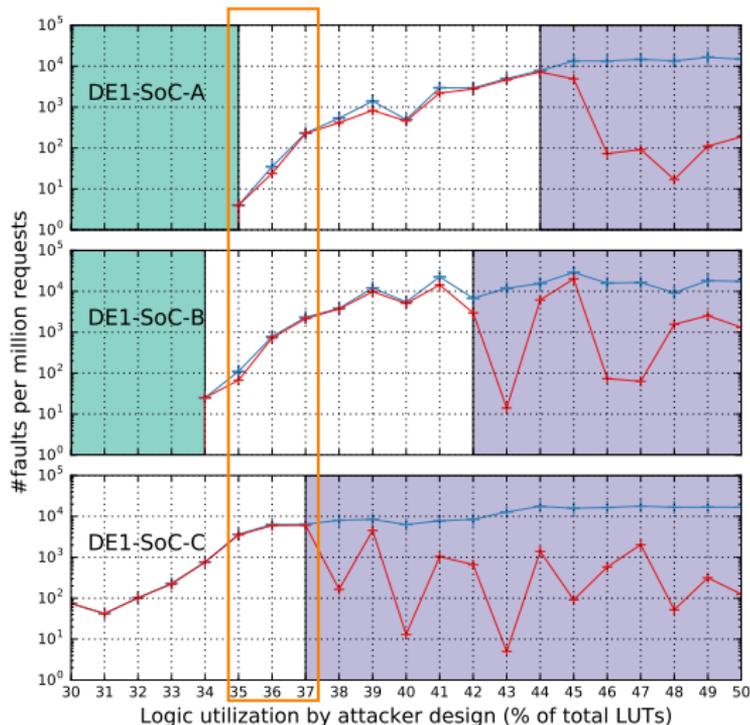
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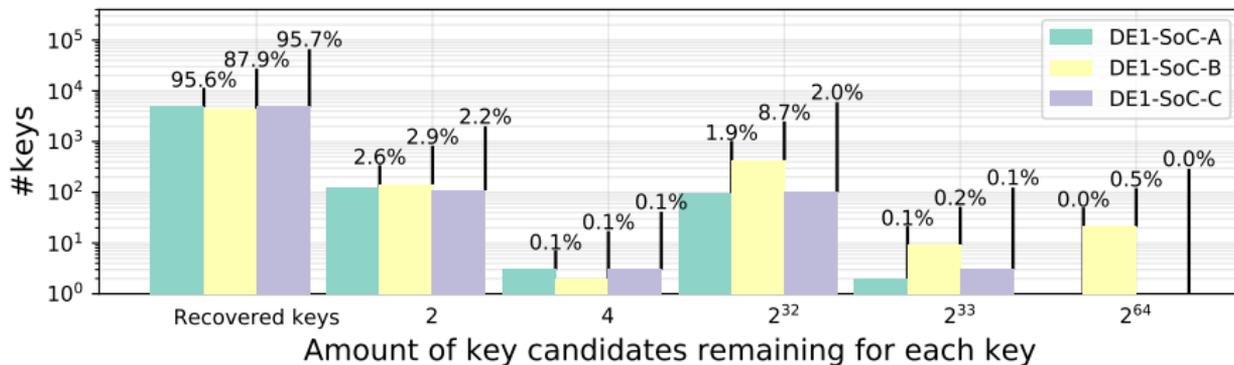
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Fault Injection Rate vs #RO



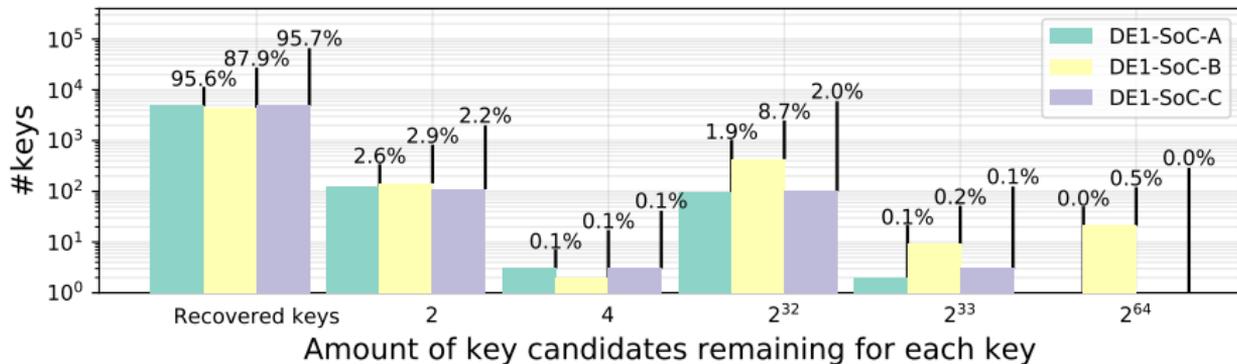
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- Process variation \Rightarrow
Different optimal #RO

Key Recovery on 5000 random keys



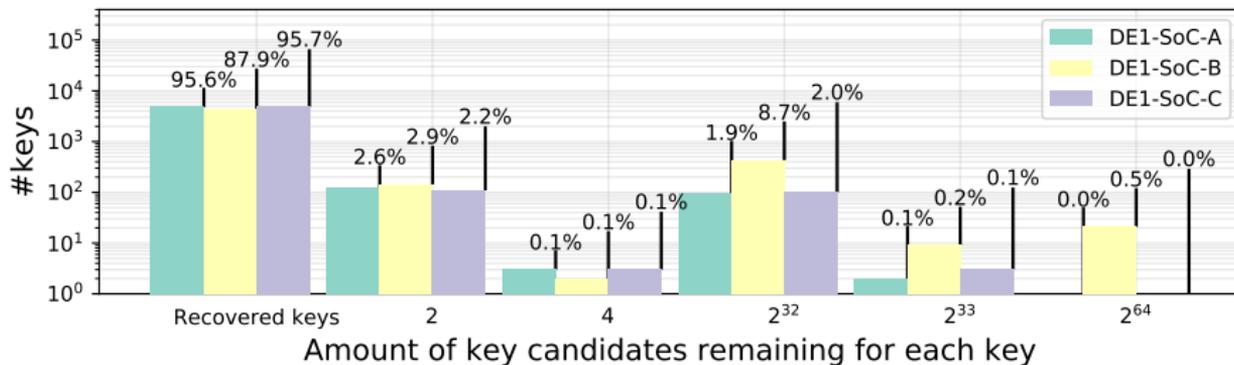
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- Unrecovered keys due to **multi-byte faults**

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- Attack on fully constrained design on DE1-SoC with $< 50\%$ resources

Discussion and Future Work

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- Alternatives to using ROs may exist
- Attack may be extended to hard cores (ARM SoC)
- Possible **mitigation**:
 - Internal sensors
 - Bitstream checking
 - Voltage islands

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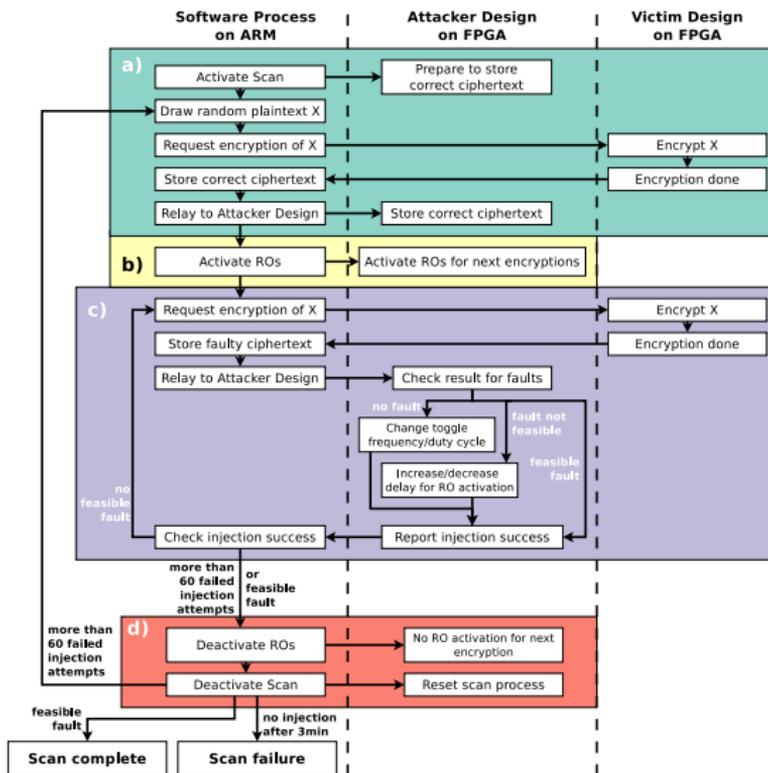
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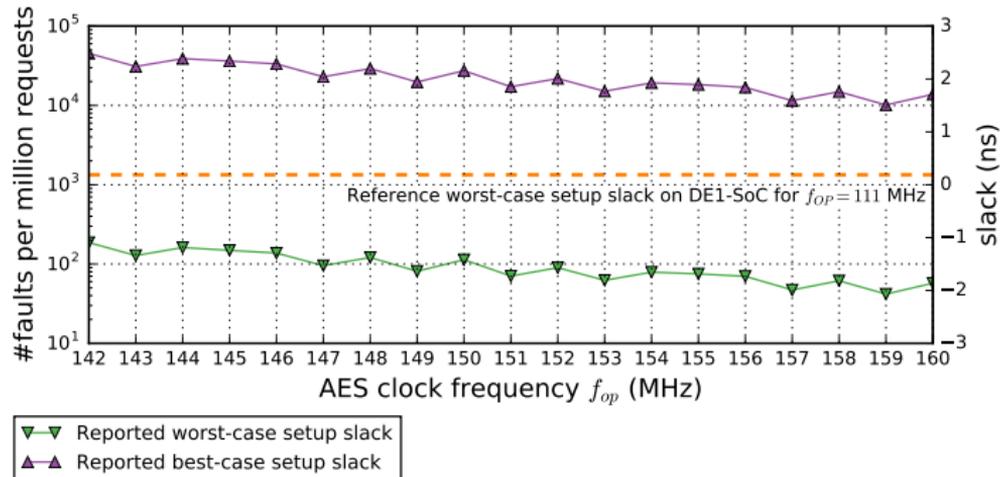
Additional Slides – Complete Scan Flow

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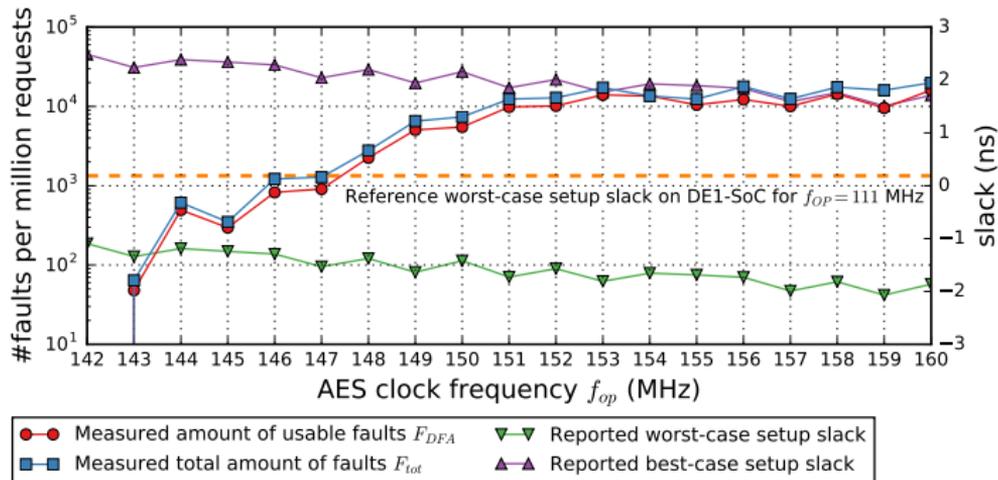
Additional Slides – Slack Dependent Analysis

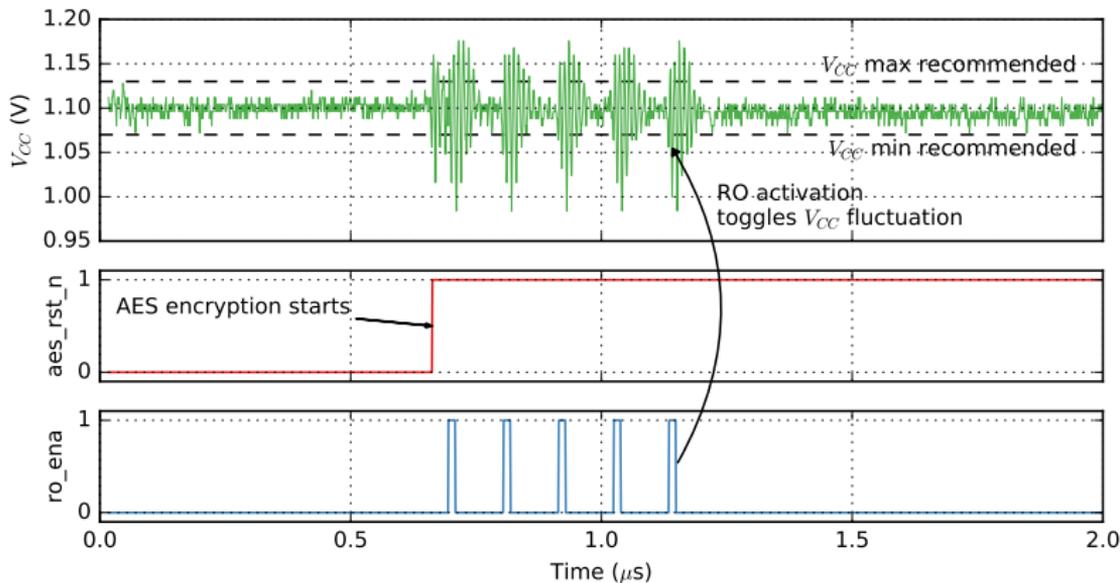
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Additional Slides – Slack Dependent Analysis

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- Externally measured FPGA supply voltage V_{CC} during fault injection
- AES reset logic signal (active low)
- RO grid activation signal

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